

**IN THE SPECIFICATION**

Please replace paragraph [0006] with the following rewritten paragraph:

[0006] A known source of failure in semiconductor devices is the generation of electron-hole pairs caused by cosmic rays or other ionizing radiation. In a DRAM device, the generation of the electron-hole pairs can change the voltage stored in a memory cell so that a stored "0" value may be changed to a "1" or a stored "1" may be changed to a "0" and thus, the value read out from the DRAM is altered. Such errors in a memory cell of a DRAM are usually present only for a short time, however, because the ~~effected~~-affected cell is typically rewritten or reset by a subsequent memory cell access.